WEST Search History

DATE: Tuesday, September 28, 2004

Hide?	Set Name	Query	Hit Count
		DB=PGPB,USPT; PLUR=NO; OP=ADJ	
☐	L52	atmel.asn. and spi	6
☐	L51	l6 and L50	1
☐	L50	(overwrit$4 or over-writ$4 or eras$3) same 149	38
☐	L49	test$3 same calibrat$3 same program$5	3318
☐	L48	(overwrit$4 or over-writ$4 or eras$3) same 147	1
☐	L47	test$3 same calibrat$3 same microcontroller$1	266
☐	L46	(overwrit$4 or over-writ$4) same 127	0
☐	L45	(overwrit$4 or over-writ$4) same (140 or 141)	1
☐	L44	wright.in. and wick.in.	0
☐	L43	L40 and L41	0
☐	L42	L40 and L24L24	0
☐	L41	load$3 with calibration program$1	37
☐	L40	load$3 with test program$1	578
☐	L39	calibration program$3 with eras$3	1
☐	L38	test program$3 with eras$3	50
☐	L37	5428770.uref.	11
☐	L36	microcontroller$1 and L35	46
☐	L35	L33 and L34	768
☐	L34	714/$.ccls.	28607
☐	L33	702/$.ccls.	24827
☐	L32	dual purpose interface	4
☐	L31	test program$1 same calibration program$1	9
☐	L30	L29 and microcontroller$1	3
☐	L29	(702/119).ccls. and (702/120).ccls.	23
☐	L28	L27 same (manufactur$3 or fabricat$3)	6
☐	L27	test$3 same calibrat$3 same microcontroller$1 same mode	54
☐	L26	test$3.clm. and L18	35
☐	L25	test$3.clm. and L22	5
☐	L24	test$3.clm. and chip.clm. and L22	0
☐	L23	test$3.clm. and manufactur$3.clm. and L22	0
☐	L22	treat.xa.	66

☐	L21	test$3.clm. and manufactur$3.clm. and L18	1
☐	L20	test$3.clm. and chip.clm. and L18	2
☐	L19	test$3.clm. and chip.clm. L18	0
☐	L18	treat.xp.	589
☐	L17	manufactur$3 same L8	47
☐	L16	(L11 or L13) and usb	3
☐	L15	L7 and L11	22
☐	L14	L7 and L13	8
☐	L13	5596734.uref.	46
☐	L12	5596734.pn.	1
☐	L11	5495593.uref.	28
☐	L10	5495593.pn.	1
☐	L9	test$3 same L8	25
☐	L8	L6 with L7	418
☐	L7	re-program$8 or reprogram$8	23470
☐	L6	microcontroller$1 or micro-controller$1	42146

DB=USPT; PLUR=NO; OP=ADJ

☐	L5	5467286.pn.	1

DB=EPAB; PLUR=NO; OP=ADJ

☐	L4	5467286.pn.	0
☐	L3	embedded.ti. and sun.in. and processor.ti.	1

DB=DWPI; PLUR=NO; OP=ADJ

☐	L2	embedded.ti. and sun.in. and processor.ti.	0
☐	L1	embedded.ti. and sun.in.	32

END OF SEARCH HISTORY